

```
### Log file for this test: /afs/hep.wisc.edu/cms/RCTlog/daffodil/EIC_2004-07-27.log ### Location of log file
```

```
#####  
##### EIC Test 3 - Write/read data to/from LUTs #####  
### Test run on 2004-07-27_16:59:06  
### HOST computer is: daffodil  
### Run executable rctCrateTest  
#####
```

```
Device to open: /dev/btp96 SBS successfully  
Device to open: /dev/btp160 booted and talked  
Device to open: /dev/btp64 to the cards in the crate  
Enter command (help for usage)>
```

```
RCT boot succeeded with 2 cards. Only the CCC and the ECI to be tested should be plugged in
```

```
Enter command (help for usage)>
```

```
Device to open: /dev/btp96  
Device to open: /dev/btp160  
Device to open: /dev/btp64
```

```
RCTCrate::initialize() : vmeReset() successful
```

```
RCTCrate::initialize() : Defined RCTClockControlCard 10000000
```

```
RCTCrate::initialize() : Defined RCTElectronIsolationCard with address 15000000
```

```
rctCrateTest: initialize() succeeded
```

Address corresponds to EIC being in slot 2

```
Cards in the crate are: 10
```

```
RCTCrate::doZeroPatternTest() : Loading EIC (f800, 15000000)
```

```
RCTCrate::doZeroPatternTest() : Verifying EIC (f800, 15000000)
```

```
RCTCrate::doIncreasingPatternTest() : Loading EIC (f800, 15000000)
```

```
RCTCrate::doIncreasingPatternTest() : Verifying EIC (f800, 15000000)
```

```
RCTCrate::doDecreasingPatternTest() : Loading EIC (f800, 15000000)
```

```
RCTCrate::doDecreasingPatternTest() : Verifying EIC (f800, 15000000)
```

```
RCTCrate::doRandomPatternTest() : Loading EIC (f800, 15000000)
```

```
RCTCrate::doRandomPatternTest() : Verifying EIC (f800, 15000000)
```

```
rctCrateTest: All tests successful
```

Compare this number to EIC barcode

```
##### EIC Test 3 End #####
```